

**Search Notes**

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Examiner

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Applicant(s)/Patent under  
Reexamination

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Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
331	16,17	4/18/2005	HLN
327	311,312	✓	✓
327	551-559	✓	✓
Update	Search	9/30/2005	HLN
Update	Search	1/10/2006	HLN
Update	Search	7/3/2006	HLN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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